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| <input type="checkbox"/> | <p>5. Determination of worst-case crosstalk noise for non-switching victims in GHz+ Interconnect Jun Chen; Lei He; Design Automation Conference, 2003. Proceedings of the ASP-DAC 2003. Asia and South Pacific 21-24 Jan. 2003 Page(s):162 - 167 Digital Object Identifier 10.1109/ASPDAC.2003.1195010 AbstractPlus Full Text: PDF(601 KB) IEEE CNF</p> |
| <input type="checkbox"/> | <p>6. Analysis of noise avoidance techniques in DSM Interconnects using a complete crosstalk n Becer, M.R.; Blaauw, D.; Zolotov, V.; Panda, R.; Hajj, I.N.; Design, Automation and Test in Europe Conference and Exhibition, 2002. Proceedings</p> |

4-8 March 2002 Page(s):456 - 463
Digital Object Identifier 10.1109/DATE.2002.998313
[AbstractPlus](#) | Full Text: [PDF](#)(400 KB) IEEE CNF

- ☐ 7. **Noise and delay uncertainty studies for coupled RC interconnects**
Kahng, A.B.; Muddu, S.; Vidhani, D.;
ASIC/SOC Conference, 1999. Proceedings. Twelfth Annual IEEE International
15-18 Sept. 1999 Page(s):3 - 8
Digital Object Identifier 10.1109/ASIC.1999.806462
[AbstractPlus](#) | Full Text: [PDF](#)(404 KB) IEEE CNF

- ☐ 8. **Aggressor alignment for worst-case crosstalk noise**
Hui Chen, L.; Marek-Sadowska, M.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 20, Issue 5, May 2001 Page(s):612 - 621
Digital Object Identifier 10.1109/43.920689
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(184 KB) IEEE JNL

- ☐ 9. **Worst-case crosstalk noise analysis based on dual-exponential noise metrics**
Jiaxing Sun; Yun Zheng; Qing Ye; Tianchun Ye;
VLSI Design, 2005. 18th International Conference on
2005 Page(s):348 - 353
Digital Object Identifier 10.1109/ICVD.2005.173
[AbstractPlus](#) | Full Text: [PDF](#)(184 KB) IEEE CNF

- ☐ 10. **A practical approach to crosstalk noise verification of static CMOS designs**
Nagaraj, N.S.; Cano, F.; Young, D.; Vohra, D.; Das, M.;
VLSI Design, 2000. Thirteenth International Conference on
3-7 Jan. 2000 Page(s):370 - 375
Digital Object Identifier 10.1109/ICVD.2000.812635
[AbstractPlus](#) | Full Text: [PDF](#)(88 KB) IEEE CNF

- ☐ 11. **False aggressors pruning using path sensitization and logic implications**
Hyungwoo Lee; Juho Kim;
Advanced System Integrated Circuits 2004. Proceedings of 2004 IEEE Asia-Pacific Conference on
4-5 Aug. 2004 Page(s):278 - 281
Digital Object Identifier 10.1109/APASIC.2004.1349471
[AbstractPlus](#) | Full Text: [PDF](#)(357 KB) IEEE CNF

- ☐ 12. **Crosstalk noise analysis in ultra deep submicrometer technologies**
Elgamel, M.A.; Tharmalingam, K.S.; Bayoumi, M.A.;
VLSI, 2003. Proceedings. IEEE Computer Society Annual Symposium on
20-21 Feb. 2003 Page(s):189 - 192
[AbstractPlus](#) | Full Text: [PDF](#)(250 KB) IEEE CNF

- ☐ 13. **A test-vector generation methodology for crosstalk noise faults**
Hashempour, H.; Yong-Bin Kim; Park, N.;
Defect and Fault Tolerance in VLSI Systems, 2002. DFT 2002. Proceedings. 17th IEEE Internation
6-8 Nov. 2002 Page(s):40 - 47
Digital Object Identifier 10.1109/DFTVS.2002.1173500
[AbstractPlus](#) | Full Text: [PDF](#)(841 KB) IEEE CNF

- ☐ 14. **Early probabilistic noise estimation for capacitively coupled interconnects**
Becer, M.R.; Blaauw, D.; Panda, R.; Hajj, I.N.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 22, Issue 3, March 2003 Page(s):337 - 345
Digital Object Identifier 10.1109/TCAD.2002.807892

[AbstractPlus](#) | [References](#) | Full Text: [PDF\(509 KB\)](#) IEEE JNL



15. Noise-constrained Interconnect optimization for nanometer technologies

Elgamel, M.A.; Tharmalingam, K.S.; Bayoumi, M.A.;
Circuits and Systems, 2003. ISCAS '03. Proceedings of the 2003 International Symposium on
Volume 5, 25-28 May 2003 Page(s):V-481 - V-484 vol.5
Digital Object Identifier 10.1109/ISCAS.2003.1206323

[AbstractPlus](#) | Full Text: [PDF\(341 KB\)](#) IEEE CNF



16. Modeling crosstalk induced delay

Chung-Kuan Tsai; Marek-Sadowska, M.;
Quality Electronic Design, 2003. Proceedings. Fourth International Symposium on
24-26 March 2003 Page(s):189 - 194
Digital Object Identifier 10.1109/ISQED.2003.1194730

[AbstractPlus](#) | Full Text: [PDF\(367 KB\)](#) IEEE CNF



17. Pre-route noise estimation in deep submicron integrated circuits

Becer, M.R.; Blaauw, D.; Panda, R.; Hajj, I.N.;
Quality Electronic Design, 2002. Proceedings. International Symposium on
18-21 March 2002 Page(s):413 - 418
Digital Object Identifier 10.1109/ISQED.2002.996781

[AbstractPlus](#) | Full Text: [PDF\(412 KB\)](#) IEEE CNF



18. Analytical modeling and characterization of deep-submicrometer Interconnect

Sylvester, D.; Chenming Wu;
Proceedings of the IEEE
Volume 89, Issue 5, May 2001 Page(s):634 - 664
Digital Object Identifier 10.1109/5.929648

[AbstractPlus](#) | [References](#) | Full Text: [PDF\(524 KB\)](#) | Full Text: [HTML](#) IEEE JNL



19. An analytical model for delay and crosstalk estimation in Interconnects under general swltc

Becer, M.; Hajj, I.N.;
Electronics, Circuits and Systems, 2000. ICECS 2000. The 7th IEEE International Conference on
Volume 2, 17-20 Dec. 2000 Page(s):831 - 834 vol.2
Digital Object Identifier 10.1109/ICECS.2000.913005

[AbstractPlus](#) | Full Text: [PDF\(348 KB\)](#) IEEE CNF



20. Statistical timing analysis of coupled Interconnects using quadratic delay-change character

Chen, T.; Hajjar, A.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 23, Issue 12, Dec. 2004 Page(s):1677 - 1683
Digital Object Identifier 10.1109/TCAD.2004.837720

[AbstractPlus](#) | [References](#) | Full Text: [PDF\(480 KB\)](#) IEEE JNL



21. Eliminating false positives in crosstalk noise analysis

Ran, Y.; Kondratyev, A.; Watanabe, Y.; Marek-Sadowska, M.;
Design, Automation and Test in Europe Conference and Exhibition, 2004. Proceedings
Volume 2, 16-20 Feb. 2004 Page(s):1192 - 1197 Vol.2
Digital Object Identifier 10.1109/DATE.2004.1269054

[AbstractPlus](#) | Full Text: [PDF\(276 KB\)](#) IEEE CNF



22. Static timing analysis of Irreversible crosstalk noise pulse faults

Phadoongsidhi, M.; Saluja, K.K.;
VLSI Design, 2004. Proceedings. 17th International Conference on
2004 Page(s):437 - 442
Digital Object Identifier 10.1109/ICVD.2004.1260961

[AbstractPlus](#) | Full Text: [PDF\(324 KB\)](#) IEEE CNF

**23. Temporofunctional crosstalk noise analysis**

Chai, D.; Kondratyev, A.; Ran, Y.; Tseng, K.H.; Watanabe, Y.; Marek-Sadowska, M.;
Design Automation Conference, 2003. Proceedings
2-6 June 2003 Page(s):860 - 863

[AbstractPlus](#) | Full Text: [PDF](#)(528 KB) IEEE CNF



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